A Static Power Model for Architects

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Overview

The static power problem

- Leakage current
- Scaling trends

A static power model: $P_{static} = V_{CC} \cdot I_{leak} \cdot N \cdot k_{design}$

Attacking static power

- Power gating
- Using slower devices
- Applying speculation

Conclusion



Sources of Power Consumption



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Technology Scaling

Dimensions reduced to increase performance and density

V_{CC} decreases each generation...

- Limit dynamic power
- Limit electric fields

...requiring lower V_T

• Gate overdrive = $V_{CC} - V_T$

Leakage increases exponentially

•
$$P_{\text{static}} = V_{\text{CC}} I_{\text{leak}} \sim exp(-V_{\text{T}})$$



Static Power Projections

Static power is an increasing fraction of total power

Today: Pentium III 1.13 GHz

- P_{total} (peak) = 41.4 watts
- P_{static} = 5.4 watts
- Static power is 13 % of total
- Higher contribution on average

This is only getting worse

• $P_{\text{static}} = P_{\text{dynamic}}$ in 3 generations



Important Characteristics of Static Power

• Exponentially increasing due to V_T scaling

Increasing faster than dynamic power

Adds to average power, not peak power

→ More expensive than dynamic power

Independent of transistor utilization

➤ Transistors are not free

Want an equivalent of $\mathbf{C} \cdot \mathbf{V_{CC}}^2 \cdot \mathbf{f}$ for static power

Develop model from the bottom-up

- Lack of data precludes a top-down "data-driven" approach
- Start from BSIM3v3.2 transistor model



$$\mathbf{I}_{\text{Dsub}} = \mathbf{I}_{\text{s0}}' \cdot \frac{W}{L} \cdot \underbrace{1 - \mathbf{v}_{\text{ds}}}_{t} \cdot e^{\frac{V_{\text{gs}} - V_{\text{T}} - V_{\text{off}}}{n \cdot v_{t}}}$$

• Apply BSIM to a single "off" (leaking) device



Oroup technology-dependent parameters together



Output to large numbers of devices



Group design-dependent parameters together

Static Power Model

Resulting power model has four parameters

- Technology-dependent (from scaling, process data)
- Design-dependent (from estimates, past designs)



The Design Constant

Represents an "average" device

- Aspect ratio (device size)
- Fraction of leaking devices
- Stacking factor

Depends on design style

Independent of technology

Allows for forward projection



Attacking Static Power

Power reduction techniques address factors in the model equation:

$$\mathbf{P}_{\text{static}} = \mathbf{V}_{\text{CC}} \cdot \hat{\mathbf{I}}_{\text{leak}} \cdot \mathbf{N} \cdot \mathbf{k}_{\text{design}}$$

Use power aware microarchitecture

- Use fewer devices
- Power gating

Employ slow devices

- Enables supply voltage reduction (voltage partitioning)
- Enables use of higher threshold voltage devices

Power Gating

Eliminate leakage by removing power to unused devices

- Analogous to clock gating
- Requires logic to determine power down/up conditions

Many power gating possibilities

- Floating point hardware
- Rare instruction decode logic
- Interrupt handling hardware

Power-up prediction problem

- Large decoupling capacitance
- Limited charging current & dl/dt
- Several cycles of power-up latency



Speculative Power Gating

Power-up latency limits power gating potential

- Do not gate power (no power savings)
- Accept power-up latency (lower performance)
- Build predictor for power-up condition

Adjustable misprediction penalties

Power/performance bias



Sample Applications

- PC based prediction for special instruction needs
- PC based prediction for L1 miss handler (L1-L2 interface)

Using Slower Devices

Trade latency and area for power

- 2× devices at 0.5× frequency
 - → Equivalent throughput with higher latency and lower total power

Reducing clock frequency helps only dynamic power

- Multiple threshold voltage technology (multiple frequency domains)
- Variable supply voltage (multiple supply voltage domains)

Architectural Issues

- Interdomain communication
- Latency tolerance

Speculation is a latency tolerance technique

- Generate speculative result more quickly than it can be determined
- Check accuracy off critical path, recover when wrong
- → Average latency is decreased

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Conclusions

Static power will become important (V_T scaling)

A high-level model is available: $P_{static} = V_{CC} \cdot I_{leak} \cdot N \cdot k_{design}$

Reducing static power also reduces dynamic power

Speculation as a power savings technique

- Speculative power gating
- Allows use of slower devices with controlled performance penalty

What can architects do to impact static power dissipation?

- Latency/throughput tradeoffs
- Design partitioning (voltage/frequency domains)
- Identify idle resources, predict the need for them
- Identify opportunities for power speculation